

## Introduction

This Test Interface is designed to probe the leads of an assembled IC. It is terminated with two 25 way male "D" type connectors and the interface will make temporary electrical contact with the leads of the device. There are 48 probes set in one direction at 0.5mm pitch.

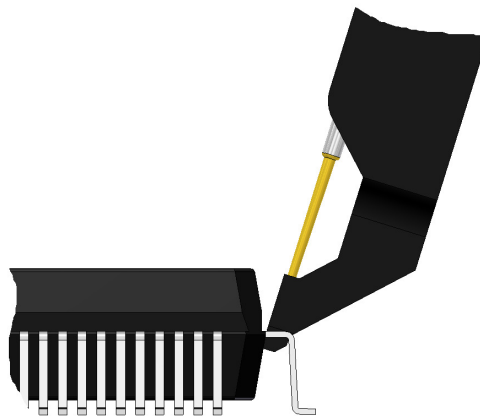
It is designed for VI testing on any 0.5mm Pitch device and when used with Diagnosys TestVue Software, the user will be guided on where to place this DTI to ensure that all leads are VI tested.

### Use as follows:

- Position the Interface as shown in figure 1 (Lining it up between the leads of the device).
- Once the DTI is located on the device, push the handle further and the high-performance microprobes will reach the leads of the device and make electrical contact.

## Features

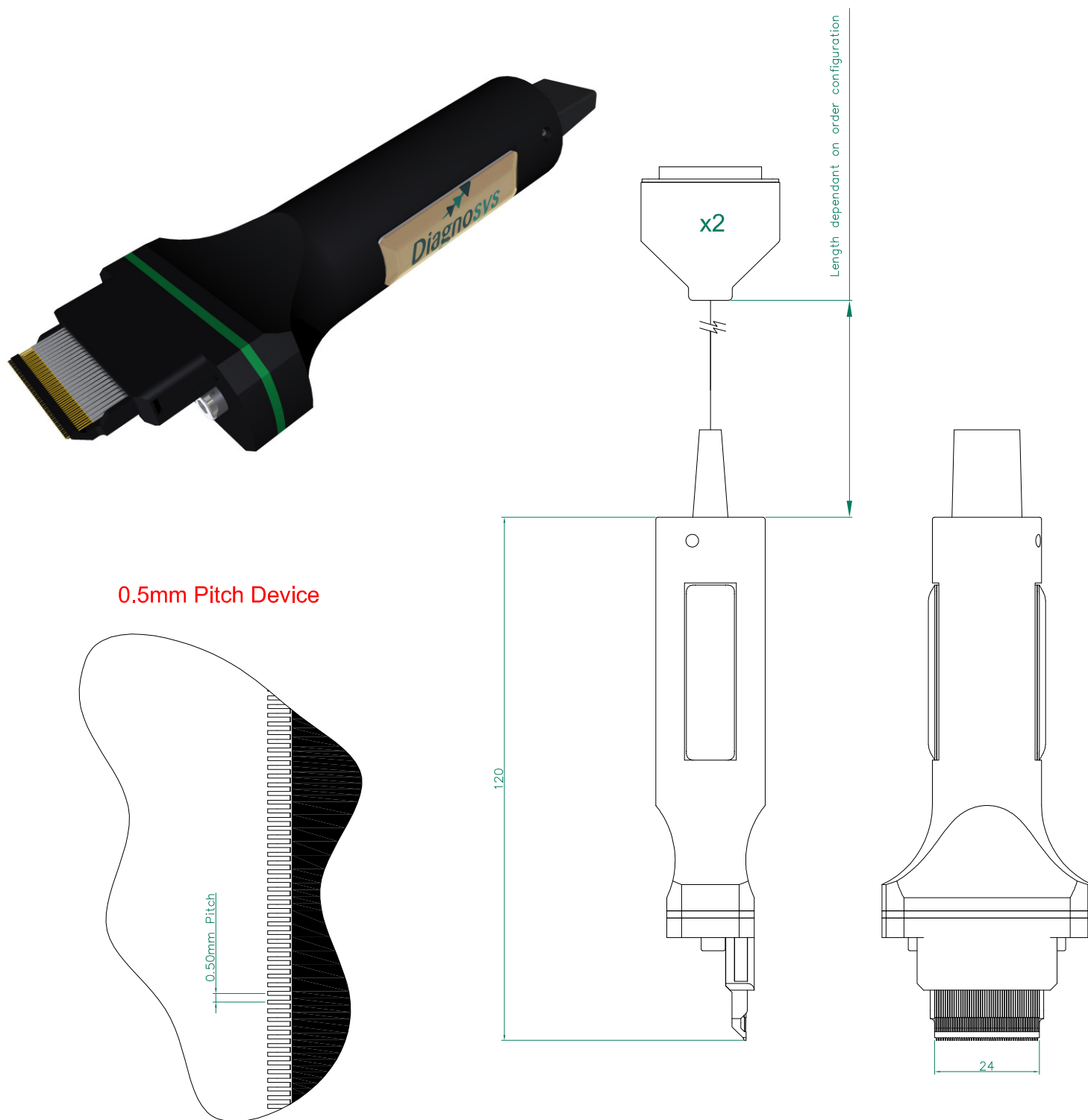
- achieves the best combination of reliability, repeatability, serviceability and user-friendliness;
- high contact pressure at probe tip, for repeatable and reliable contact;
- high reliability and long life interchangeable microprobes;
- sweeping action gold plated contacts, for reliable contact and low ohmic resistance of interconnections;
- high current rating (for single channel, in ambient air with 70°F [20°C]) : 1.5A
- impact, solvent and temperature resistant plastics, with low friction;
- wide range of operating temperatures (commercial): [0°C to +70°C]
- packaged in a hard wearing, high resistance to damage Polypropylene case with foam insets, the Test Interface can withstand high impact in transit.
- case can be used for safe storage when the Test Interface is not in use, and subsequent transport.



*figure 1*

## Specification

- It will accommodate 0.5mm Pitch Devices with a thickness of 1mm and greater;
- Maximum number of interconnections per insertion (channels): 48
- Current rating, with all contacts loaded (maximum continuous current, non inductive): 0.5A /channel;
- Contact resistance (average): 80 m  $\Omega$  /channel;
- Insulation resistance: 5M  $\Omega$  Min.
- Volume resistivity of plastic parts :  $10^{15}$   $\Omega$ -cm @ 50%RH.
- Fatigue life of probes: Min. 1,000,000 cycles at normal working distance;
- Working distance (normal stroke): 2.0mm;
- Probe force at point of contact (normal stroke - three contacts / probe): 0.25N



All DIMS shown in mm

## Maintenance

The Test Interface Head is maintenance free. The microprobes are self-cleaning. Immersion in water or contact between microprobes and any liquids should be avoided, as this could severely reduce the working life of microprobes.

Contamination is the primary cause of probe contact problems. This is generally caused by flux left as a residue on circuit boards. Other probe contaminants such as dust, fluff, oil and grime can also cause problems in other areas. Light brushing of the tips of the probes with nylon, bristle or soft metal brushes will dislodge most contaminants.